

Notice of References Cited	Application/Control No. 09/783,246	Applicant(s)/Patent Under Reexamination HUTTON, MICHAEL D.	
	Examiner Thomas H. Stevens	Art Unit 2123	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hutton et al., "Characterization and Parameterized Random Generation of Digital Circuit" 33 rd Design Automation Conference 1996 Las Vegas, Nev. pg.94-99.
	V	Hutton et al., "Characterization and Parameterized Random Generation of Digital Circuit" Thesis 1997 University of Toronto. pg.123 pages.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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